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LIST OF ART CITED BY APPLICANT (PTO-1449)				P-0751		APPLN. SERIAL NO. New U.S. Patent Application		
				APPLICANT(S) Sang-Ik LEE; Eun-Jeong KIM and Yeon-Yi HWANG				
				FILING DATE April 20, 2005		GROUP To be assigned		
U.S. PATEN	T DOCUMENTS	· .	-					
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	"INVENTOR NAME		CLASS	SUBCLASS		ING
M	2,267,486	9/24/1940-	J.B. West		62	89	<u> </u>	
		12-23-	1941			1		
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MO	JP2150682	6/8/1990	Japan				AB	ļ
	EP0248370B1 JP11083300	7/03/1991	Europe			<u> </u>	• • •	ļ
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

KE 1-25-2008